

# DESIGN OBJECTIVES

## High Voltage Detective Connector 108-32179

The product described in this document has not been fully tested to ensure conformance to the requirements outlined herein. TE Connectivity makes no representation or warranty, express or implied that the product will comply with these requirements. Further, TE Connectivity reserves the right these requirements based on the results of additional testing and evaluation. Contact TE Connectivity Engineering for further information. If necessary, this document will become the Product Specification at successful completion of testing.

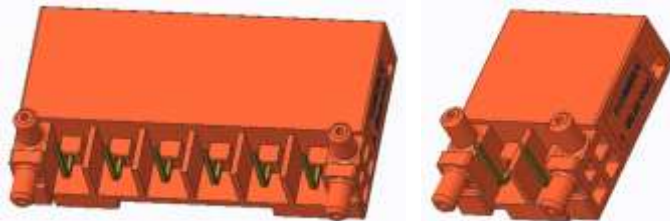
### 1. Scope:

#### 1.1 Content

This specification covers the requirements for product performance, test methods and quality assurance provisions of High Voltage Detective Connector.

#### MQS 2P/6P HEADER ASSY RIGHT ANGLE/VERTICAL ANGLE:


- TE PN: 2322946-1/2322946-2 (6P RIGHT ANGLE)
- 2322949-1/2322949-2 (6P VERTICAL ANGLE)
- 2-2322946-1/2-2322946-2 (2P RIGHT ANGLE)
- 2-2322949-1/2-2322949-2 (2P VERTICAL ANGLE)



#### MQS 2P/6P HOUSING:

- TE PN: 2322948-1/2322948-2 (6P)
- 2-2322948-1/2-2322948-2 (2P)
- Terminal: 5-963715-1 (wire size: 0.5mm<sup>2</sup>)



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				CHK C.ZHOU 19NOV2018					
				APP W.WU 20NOV2018		NO. 108-32179		REV A	LOC ES
A		Released	W.Z	20NOV2018	PAGE 1 of 11	TITLE High Voltage Detective Connector			
LTR		REVISION RECORD	DR	DATE					

## 2. Applicable Documents:

The following documents form a part of this specification to the extent specified herein. In the event of conflict between the requirements of this specification and the product drawing, product drawing shall be taken precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

### 2.1 Specifications:

- A. USCAR-2-2013
- B. USCAR-37-2008
- C. GMW3172-2015
- D. GMW3191-2012
- E. DIN IEC 68 2-20
- F. IEC 60068-2-54
- G. IEC 60512-5-2
- H. IEC 60529
- I. EIA 364-70A

## 3. Requirements:

### 3.1 Design and Construction

Product shall be of the design, construction and physical dimensions specified in the applicable product drawing.

### 3.2 Materials

MQS 2P/6P HEADER ASSY RIGHT ANGLE/ VERTICAL ANGLE:

Housing: PPA-GF30 V0 (Zytel HTN FR52G30NH NC010)

Terminal: CuZn30 H04 Plating: Sn over Ni

MQS 2P/6P HOUSING:

PA6-GF20 V0 (Durethan BKV 20 FN01)

### 3.3 Ratings:

A. Operating Temperature Range: Class 3 (-40°C to +125°C)

B. Nominal operating voltage: 1000V DC

For application at higher voltage please contact TE Connectivity.

Current: 1A Max at 125°C

C. Vibration Range: Class 1

GWM3172-2015 9.3.1.3 Mounting Location Underhood Sprung Masses



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D. Sealing range: IP XXB

### 3.4 Quality Assurance Provision

A. Sample Preparation:

The test samples to be used for the test shall be prepared by random selection from the current production. No sample shall be reused, unless otherwise specified.


B. Test Condition:

All the test shall be performed under any combination of the following test condition, unless otherwise specified:

Room temperature:  $23\pm 5^{\circ}\text{C}$

Relative humidity: 45~75%

Atmospheric pressure: 860~1060 mbar

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## 3.5 Requirements and Procedures Summary

**General Test**

Para.	Test items	Requirements	Procedures
3.5.1	Visual inspection	No defect and non-functionality. Such as cracks, tarnishing, flash, etc.	Visually, Dimensionally and functionally inspected per applicable inspection plan.  USCAR-2 Section 5.1.8 Visual inspection.
3.5.2	Heat Resistance to Reflow Soldering	Note any blisters, deformation/warping, melting or physical damage (visual inspection by 30X max magnification).	Reflow profile refers to APPENDIX 5.1
3.5.3	Connector and/or Terminal Cycling	Complete mate and un-mate each connector or terminal pair 10times	USCAR-2 Section 5.1.7 Connector and/or Terminal Cycling

**Mechanical Test**

Para.	Test items	Requirements	Procedures
3.5.4	Terminal to Connector Insertion Force (TPA in open position)	TPA in Open Position: Insertion Force $F \leq 30N$	USCAR-2 Section 5.4.1.3 A Insertion Force
3.5.5	Terminal to Connector Insertion Force (Forward stop)	$F \geq 50N$ or wire buckling	USCAR-2 Section 5.4.1.3 A Insertion Force
3.5.6	Terminal from Connector Retention Force- Primary lock only	0.64mm Terminal: $F \geq 30N$	USCAR-2 Section 5.4.1.3 B Retention Force
3.5.7	Terminal from Connector Retention Force- Primary Lock and TPA/PLR	0.64mm Terminal: 1. Primary + Secondary Lock after Moisture Conditioning, $F \geq 60N$ 2. Primary + Secondary Lock after Temp/Humidify and HTE, $F \geq 50N$	USCAR-2 Section 5.4.1.3 B Retention Force
3.5.8	Connector Mating force	$F \leq 75N$	USCAR-2 Section 5.4.2 Mating Force
3.5.9	Connector Un-mating Force	$F \leq 75N$	USCAR-2 Section 5.4.2 Un-Mating Force
3.5.10	Connector to Connector Latch Retention Force	Using connector pairs without wires and terminals $F \geq 80N$	GMW3191 4.2.18 Locked Connector Disengagement Force
3.5.11	Polarization Feature Effectiveness	3X Maximum value of mating force ( $60N \leq F \leq 150N$ ). No damage for connector and no electrical contact shall be made between male/female terminals.	USCAR-2 Section 5.4.4 Polarization Feature Effectiveness
3.5.12	Header Pin Retention	15N Min	USCAR-2, Section 5.7.1 Header Pin Retention



### Electrical Test

Para.	Test items	Requirements	Procedures
3.5.13	Circuit Continuity Monitoring	There must be no instance in which the resistance of any terminal pair exceeds 7Ω for more than 1 microsecond.	USCAR-2 Section 5.1.9 Circuit Continuity Monitoring
3.5.14	Dry Circuit Resistance	Contact Resistance 20mΩ Max	USCAR-2 Section 5.3.1 Dry Circuit Resistance
3.5.15	Voltage Drop	Maximum Voltage Drop 50mV	USCAR-2 Section 5.3.2 Voltage Drop
3.5.16	Isolation Resistance	Resistance ≥ 100 MΩ at 1000VDC	USCAR-2 Section 5.5.1 Isolation Resistance.
3.5.17	Dielectric Withstanding	There shall be no dielectric break-down or flash over between cavities or between circuits in cavities and the outside of the connector or shield.  Leakage Current 1mA Max at 3000VAC	USCAR 37, Section 5.5.2  3000VAC applied to the samples.  Dielectric withstanding voltage test Un-sealed connector pairs shall be conditioned for ≥3hrs at lab ambient conditions prior to conducting dielectric strength testing.
3.5.18	Temperature Rise	Test Current: 1A Ambient Temp: 125°C  The measured temperature of the terminal pair interface must not exceed +5°C rise over ambient temperature. Contact Resistance 20mΩ Max.	EIA 364-70A Method 1 IEC 60512-5-2

### Environmental Test

Para.	Test items	Requirements	Procedures
3.5.19	Mechanical Shock and Vibration	Connector function meets the needs of Para. 3.5.13, 3.5.14, 3.5.15, 3.5.1	USCAR-2 Section 5.4.6 Mechanical shock V1 GWM3172-2015 9.3.1.3 Mounting Location Underhood Sprung Masses Profile refers to APPENDIX 5.2, 5.3
3.5.20	Thermal Shock	Connector function meets the needs of Para. 3.5.13, 3.5.14, 3.5.15, 3.5.16, 3.5.17, 3.5.1	USCAR-2 Section 5.6.1 Thermal Shock 300 cycles, -40°C~+125°C
3.5.21	Temperature/ Humidity Cycling	Connector function meets the needs of Para. 3.5.14, 3.5.15, 3.5.16, 3.5.17, 3.5.7, 3.5.1	USCAR 2, Section 5.6.2 Temperature 125°C, 40 cycles Profile refers to APPENDIX 5.4
3.5.22	High Temperature Exposure	Connector function meets the needs of Para. 3.5.14, 3.5.15, 3.5.16, 3.5.17, 3.5.1	USCAR 2, Section 5.6.3. Temperature 125°C, 1008hours.
3.5.23	Protection against accidental contact, IPXXB (Finger)	No contact between HV circuits and 12mm dia. Finger probe at 10 N±10%	IEC 60529, section 12



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<b>Solderability Test</b>			
Para.	Test items	Requirements	Procedures
3.5.24	Solderability – Wetting Test	Surface must be 100% wetted, surface defects are not allowed (visual inspection by 4X to 25X magnification).	<p>IEC 60068-2-54 (wetting balance test method)</p> <p>Pre-ageing:            50% of the devices: 1h steam aging by IEC 60068-2-20, chapter 4.1.1 method 1a            50% of the devices: 4h 155°C by IEC 60068-2-20, chapter 4.1.1 method 3a</p> <p>Solder bath temperature:            235 ± 3°C (lead soldering)            245 ± 3°C (lead-free soldering)</p> <p>Dip in duration: 30sec ± 15sec</p> <p>Immersion depth: according to solder area of header pins</p>
3.5.25	Solderability – De-wetting Test	De-wetting is not allowed (visual inspection by 4X to 25X magnification).	<p>According to IEC 60068-2-20 5.2.5</p> <p>Pre-ageing: None</p> <p>Solder bath temperature:            260 ± 3°C (lead soldering)            270 ± 3°C (lead-free soldering)</p> <p>Dip in duration: 2x 5 sec ± 0,5 sec</p> <p>Immersion depth: according to solder area of header pins</p>

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## 3.6 Product Qualification Test and Sequences

Test or examination	Test Group						
	1	2	3	4	5	6	
3.5.1 Visual Inspection	1, 5	1, 4	1, 6	1, 4	1, 4	1, 4	
3.5.2 Heat Resistance to Reflow Soldering		2	2	2	2	2	
3.5.3 Connector and/or Terminal Cycling							
3.5.4 Terminal to Connector Insertion Force (TPA in open position)	2						
3.5.5 Terminal to Connector Insertion Force (Forward stop)	3						
3.5.6 Terminal from Connector Retention Force- Primary lock only	4						
3.5.7 Terminal from Connector Retention Force- Primary Lock and TPA/PLR			5				
3.5.8 Connector Mating Force			3				
3.5.9 Connector Un-mating Force			4				
3.5.10 Connector to Connector Latch Retention Force		3					
3.5.11 Polarization Feature Effectiveness				3			
3.5.12 Header Pin Retention					3		
3.5.13 Circuit Continuity Monitoring							
3.5.14 Dry Circuit Resistance						3	
3.5.15 Voltage Drop							
3.5.16 Isolation Resistance							
3.5.17 Dielectric withstanding							
3.5.18 Temperature Rise						3	
3.5.19 Mechanical Shock and Vibration							
3.5.20 Thermal Shock							
3.5.21 Temperature/Humidity Cycling							
3.5.22 High Temperature Exposure							
3.5.23 Protection against accidental contact, IPXXB (Finger)							
3.5.24 Solderability – Wetting							
3.5.25 Solderability – De-wetting							
Sample Size	6P Connector	4	10	10	4	4	4
	6P Terminal	24	-	24	-	-	-
	2P Connector	5	10	10	4	4	5
	2P Terminal	10	-	10	-	-	-

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## 3.6 Product Qualification Test and Sequences (continued)

Test or examination	Test Group							
	7	8	9	10	11	12	13	
3.5.1 Visual Inspection	1, 8	1, 12	1, 13	1, 12	1, 3	1, 3	1, 3	
3.5.2 Heat Resistance to Reflow Soldering	2	2	2	2				
3.5.3 Connector and/or Terminal Cycling	3	3	3	3				
3.5.4 Terminal to Connector Insertion Force (TPA in open position)								
3.5.5 Terminal to Connector Insertion Force (Forward stop)								
3.5.6 Terminal from Connector Retention Force- Primary lock only								
3.5.7 Terminal from Connector Retention Force- Primary Lock and TPA/PLR			12					
3.5.8 Connector Mating Force								
3.5.9 Connector Un-mating Force								
3.5.10 Connector to Connector Latch Retention Force								
3.5.11 Polarization Feature Effectiveness								
3.5.12 Header Pin Retention								
3.5.13 Circuit Continuity Monitoring	5	7						
3.5.14 Dry Circuit Resistance	4, 6	4, 8	4, 8	4, 8				
3.5.15 Voltage Drop	7	9	9	9				
3.5.16 Isolation Resistance		5, 10	5, 10	5, 10				
3.5.17 Dielectric withstanding		6, 11	6, 11	6, 11				
3.5.18 Temperature Rise								
3.5.19 Mechanical Shock and Vibration	5							
3.5.20 Thermal Shock		7						
3.5.21 Temperature/Humidity Cycling			7					
3.5.22 High Temperature Exposure				7				
3.5.23 Protection against accidental contact, IPXXB (Finger)					2			
3.5.24 Solderability – Wetting						2		
3.5.25 Solderability – De-wetting							2	
Sample Size	6P Connector	10	10	10	10	4	-	-
	6P Terminal	-	-	24	-	-	10	10
	2P Connector	10	10	10	10	4	-	-
	2P Terminal	-	-	10	-	-	10	10



## 4. QUALIFICATION TEST

### 4.1 Sample selection


Samples shall be prepared in accordance with applicable specification.

### 4.2 Test sequence

Qualification test shall be conducted as sequence specified in table of section 3.6.

### 4.3 Requalification test

If changes significantly affecting form, fit or function are made to product or manufacturing process, product assurance shall co-ordinate requalification testing, consisting of all or part of original testing sequence as determined by developments, product, quality and reliability engineering.

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5. APPENDIX

5.1 Reflow Profile (see Fig. 1)

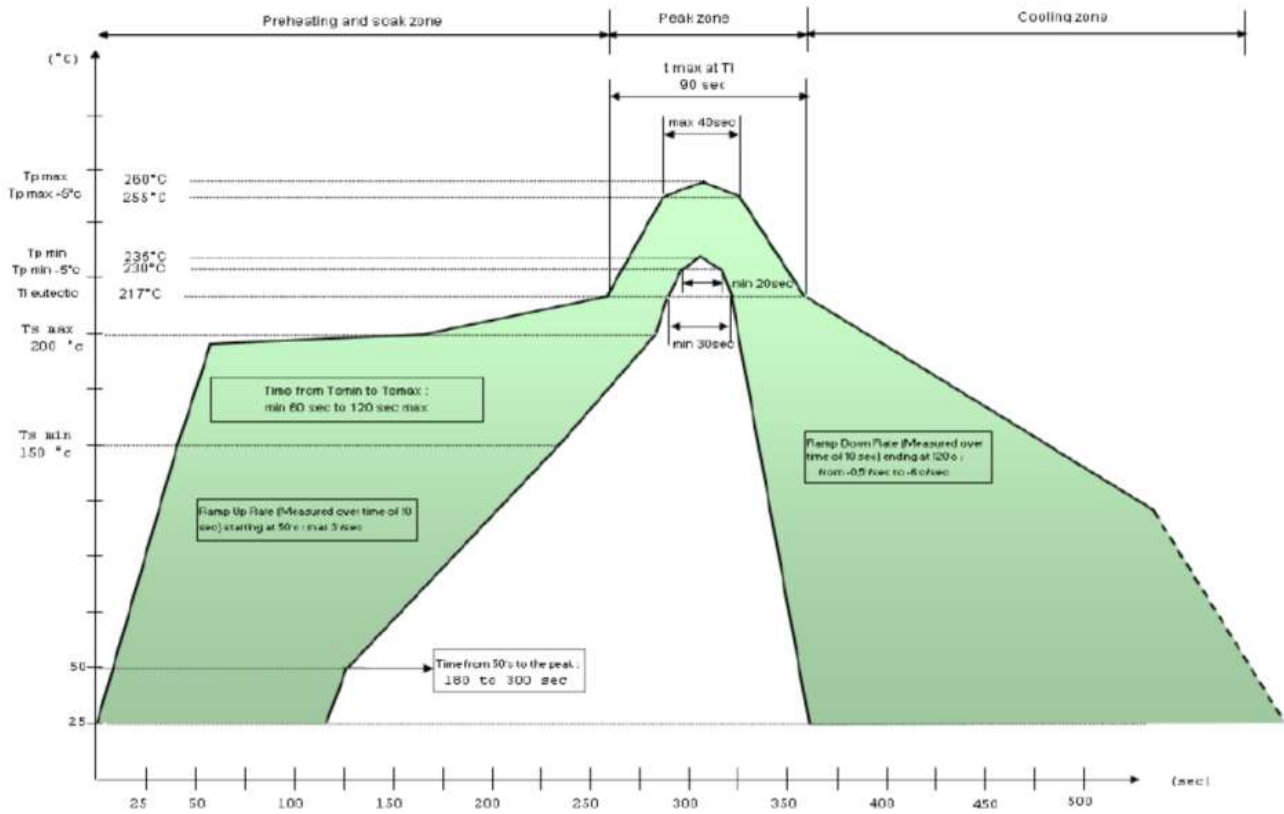


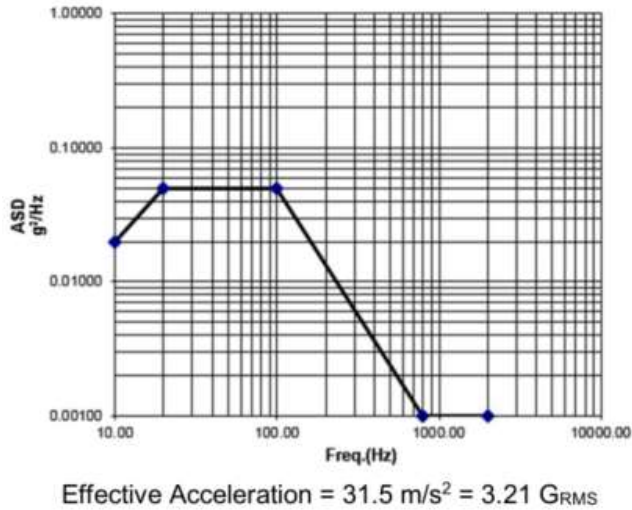
Fig. 1

5.2 Mechanical Shock Schedule (see Fig. 2)

Vibration Class	Shocks per Axis	Wave Shape	Direction (+/-)	Duration (ms)	Acceleration (g)
V1	10	Half Sine Wave	Positive	5 ~ 10	35

Fig. 2

5.3 Random Vibration Profile for Underhood Sprung Masses (see Fig. 3)



Frequency	Power Spectral Density
10 Hz	$1.9324 \text{ (m/s}^2\text{)}^2\text{/Hz} = 0.0200 \text{ g}^2\text{/Hz}$
20 Hz	$4.8085 \text{ (m/s}^2\text{)}^2\text{/Hz} = 0.0500 \text{ g}^2\text{/Hz}$
100 Hz	$4.8085 \text{ (m/s}^2\text{)}^2\text{/Hz} = 0.0500 \text{ g}^2\text{/Hz}$
800 Hz	$0.0962 \text{ (m/s}^2\text{)}^2\text{/Hz} = 0.0010 \text{ g}^2\text{/Hz}$
2000 Hz	$0.0962 \text{ (m/s}^2\text{)}^2\text{/Hz} = 0.0010 \text{ g}^2\text{/Hz}$

Fig. 3

5.4 Temperature/Humidity Cycling Schedule (see Fig. 4)

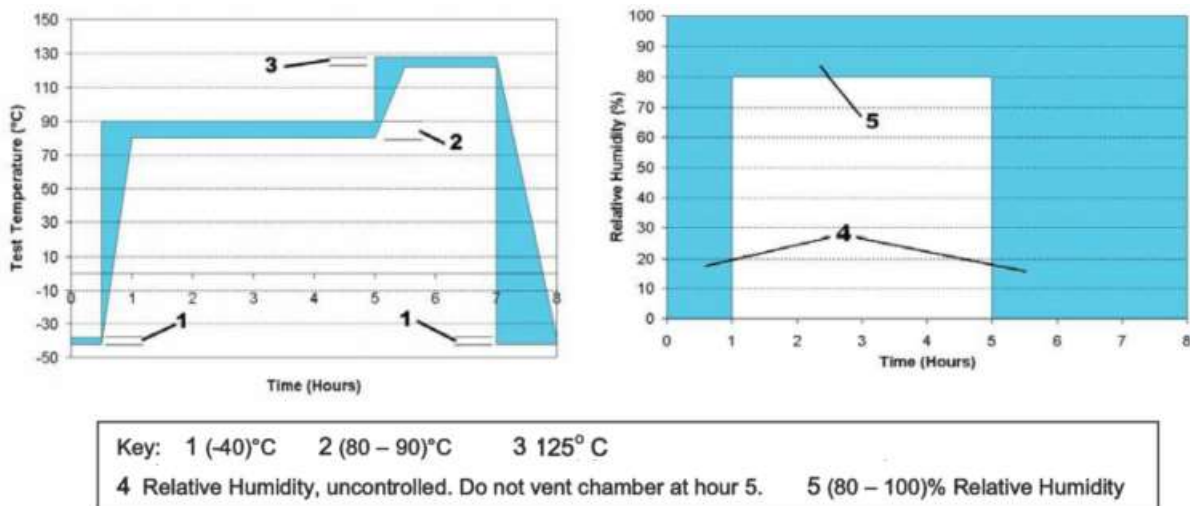


Fig. 4